

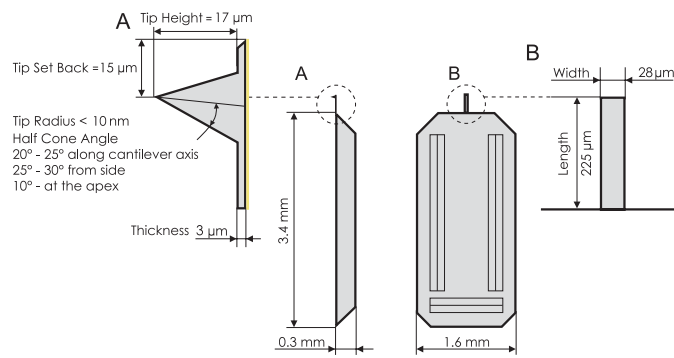


# AFM probe Model: Multi75AI-G



This probe has alignment grooves on the backside of the holder chip.

- Force Modulation, Pulsed Force Mode (PFM)
- Rotated Monolithic Silicon Probe  
Symmetric Tip Shape  
Chipsize: 3.4 x 1.6 x 0.3 mm
- Coating: Aluminium reflex coating, 30 nm thick
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	75 kHz	+/- 15 kHz
Force Constant	3 N/m	1 - 7 N/m
Cantilever Length	225 $\mu\text{m}$	+/- 10 $\mu\text{m}$
Mean Width	28 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Thickness	3 $\mu\text{m}$	+/- 1 $\mu\text{m}$
Tip Height	17 $\mu\text{m}$	+/- 2 $\mu\text{m}$
Tip Set Back	15 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Tip Radius	< 10 nm	
Coating	30 nm thick Aluminium coating	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	

Order Code	Units in Package	Coating	Price
Multi75AI-G-10	10 pieces	Aluminium Reflex	\$210
Multi75AI-G-50	50 pieces	Aluminium Reflex	\$890